

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

219587US90

SERIAL NO.

10/072,866

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Masato HAMATANI, et al.

FILING DATE

February 12, 2002

GROUP

2851

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
PT	AA	6,248,486	06/19/2001	DIRKSEN, et al.	1		
PT	AB	2002/0008869 A1	01/24/2002	VAN DER LAAN, et al.	1		
PT	AC	2002/0036758 A1	03/28/2002	DE MOL, et al.	1		
PT	AD	2002/0191165 A1	12/19/2002	BASELMANS, et al.	1		
PT	AE	5,978,085	11/02/1999	SMITH, et al.	1		
PT	AF	6,078,554	06/20/2000	OOTAKI, et al.	1		
PT	AG	6,118,535	09/12/2000	GOLDBERG, et al.	1		
PT	AH	6,100,978	08/08/2000	NAULLEAU, et al.	1		
PT	AI	2002/0001071 A1	01/03/2000	NOMURA, et al.	1		
PT	AJ	5,754,299	05/19/1998	SUGAYA, et al.	1		
PT	AK	6,329,112	12/11/2001	FUKUDA, et al.	1		

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
PT	AK	1 160 626	12/05/2001	EUROPE		
PT	AL	WO 00/31592	06/02/2000	WIPO		
PT	AM	1 128 217	08/29/2001	EUROPE		
PT	AN	10-154657	06/09/1998	Japan (w/ English abstract)		x
PT	AO	2000-121491	04/28/2000	Japan (w/ English abstract)		x
PT	AP	WO 99/60361	11/25/1999	WIPO (w/ English abstract)		x
PT	AQ	1 079 223	02/28/2001	EUROPE		
PT	AR	11-118613	04/30/1999	Japan (w/ English abstract)		x
PT	AS	6-235619	08/23/1994	Japan (w/ English abstract)		x
PT	AT	5-296879	11/12/1993	Japan (w/ English abstract)		x
PT	AU	2000-47103	02/18/2000	Japan (w/ English abstract)		x
PT	AV	2000-331923	11/30/2000	Japan (w/ English abstract)		x
PT	AW	11-233424	08/27/1999	Japan (w/ English abstract)		x
PT	AX	198 20 785 A1	10/21/1999	Germany		x
PT	AY	2000-121491	04/28/2000	Japan (w/ English abstract and translation)	x	
PT	AZ	2000-146757	05/26/2000	Japan (w/ English abstract and machine translation)	x	
PT	BA	2000-266640	09/29/2000	Japan (w/ English abstract and machine translation)	x	
PT	BB	WO 00/55890	09/21/2000	WIPO (w/ English abstract)		x
PT	BC	2001-230193	08/24/2001	Japan (w/ English abstract and machine translation)	x	
PT	BD	1 160 626 A1	12/05/2001	Europe		
PT	BF	1 355 140 A1	10/22/2003	Europe (corresponding to U.S. Application 10/608,032)		
PT	BG	1 359 608 A1	11/05/2003	Europe		
PT	BH	WO 02/50506 A1	06/27/2002	WIPO (w/ English abstract)		x

☒ Additional References sheet(s) attached

Examiner

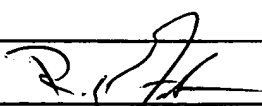
Date Considered

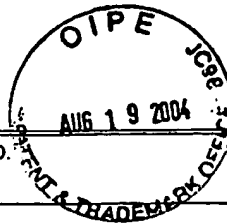
R-17-c4

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



SHEET 2 OF 2

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219587US90		SERIAL NO. 10/072,866	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Masato HAMATANI, et al.			
				FILING DATE February 12, 2002		GROUP 2851	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
P1	AAA	Winter 1998 MICROLITHOGRAPHY WORLD pages 11-20 Authors: Donis G. Flaggello and Bernd Geh Title: "The influence of lens aberrations in lithography"					
P2	AAB	Journal of Vacuum Science & Technology B: Microelectronics Processing and Phenomena, American Vacuum Society, New York, NY, US, vol. 16, no. 6, November 1998 (1998-11) pages 3435-3439 Authors: K. Goldberg, et al. Title: "High-accuracy interferometry of extreme ultraviolet lithographic optical system"					
P3	AAC	SPIE Microlithography Seminar, pages 1-14 Authors: Donis G. Flaggello, et al. Title: "TOWARDS A COMPREHENSIVE CONTROL OF FULL-FIELD IMAGE QUALITY IN OPTICAL PHOTOLITHOGRAPHY"					
	AAD						
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	AAK						
	AAL						
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	AAN						
	AAO						
	AAP						
	AAQ						
Examiner 				Date Considered 10-17-04			
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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219587US90		SERIAL NO. 10/072,866	
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				FILING DATE February 12, 2002		GROUP 2851	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Pt</i>	AA	5,807,647	09/15/1998	K. HASHIMOTO			
<i>Pt</i>	AB	5,321,493	06/14/1994	K. KAMON			
<i>Pt</i>	AC	4,786,166	11/22/1988	C. G. KROKO			
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>Pt</i>	AO	0 267 721	05/18/1988	EUROPE			
<i>Pt</i>	AP	0 338 200	10/25/1989	EUROPE			
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>P. J. Fink</i>					Date Considered <i>10-17-04</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							